

1. Scope

This specification is applies to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 100V to 5KV.

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product compliant with the RoHS.)

2. Parts Number Code



(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(2)Chip Size

· / 📕		
Code	Length×Width	unit : mm(inch)
0201	0.60× 0.30	(.024× .011)
0402	1.00× 0.50	(.039× .020)
0603	1.60× 0.80	(.063× .031)
0805	2.00× 1.25	(.079× .049)
1206	3.20× 1.60	(.126× .063)
1210	3.20× 2.50	(.126× .098)
1808	4.60× 2.00	(.181× .079)
1812	4.60× 3.20	(.181× .125)
1825	4.60× 6.35	(.181× .250)
2208	5.70× 2.00	(.220× .197)
2211	5.70× 2.80	(.220× .110)
2220	5.70× 5.00	(.220× .197)
2225	5.70× 6.35	(.220× .250)

(5)Capac	(5)Capacitance Tolerance								
Code	Tolerance	Nominal Capacitance							
В	± 0.10 pF	Less Than 10 pF							
С	± 0.25 pF	(Include 10 pF)							
D	± 0.50 pF	_							
F	± 1.00 pF	_							
F	± 1.00 %	More Than 10 pF							
G	± 2.00 %	_							
J	± 5.00 %	_							
K	± 10.0 %	_							
М	± 20.0 %	_							
Z	+80/-20 %								

(6)Rated Voltage

Code	Temperature	Temperature	Temperature
0000	Characteristic	Range	Coefficient
	Characteristic	nange	Coemcient
N	NPO	-55°C ~+125°C	30 ppm /°C
L	SL	-30 ℃ ~+85℃	+350~-1000ppm
Х	X7R	-55℃~+125℃	± 15%
В	X5R	-55° ℃ ~+85°℃	± 15%
S	X6S	-55°C ~+105°C	± 22%
Y	Y5V	-30 ℃ ~+85℃	+22/-82%
Ζ	Z5U	+10°C ~+85°C	+22/-56%
Е	Y5U	-30 ℃~+85℃	+22/-56%

unit :pico farads(pF)
Nominal Capacitance (pF)
5.0
12.0
150.0
2,200.0
47,000.0
470,000.0
1,000,000.0
10,000,000.0

%. If there is a decimal point, it shall be expressed by an English capital letter R

Code	Rated Voltage (Vdc)
101	100
201	200
251	250
501	500
631	630
102	1,000
202	2,000
252	2,500
302	3,000
502	5,000

(7)Tapping

Code	Туре
Т	Tape & Reel
В	Bulk



3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolera	ance	Nominal Capacitance
Ι	NPO / SL	Less Then 10 pF B (± 0.10 pF)		0.5,1,1.5,2,2.5,3
			C (± 0.25 pF)	0.5,1,1.5,2,2.5,3,3.5,4,4.5,5
			D (± 0.50 pF)	5,6,7,8,9,10
			F (± 1.00 pF)	6,7,8,9,10
		More Than 10 pF	F (±1.00 %)	E-12, E-24 series
			G (±2.00 %)	
			J (± 5.00 %)	
			K (± 10.0 %)	
Π	X7R/X5R/X7E	K (± 10.0 %), M (± 20.0 %)		E-3, E-6 series
	Y5V	M (± 20.0 %), Z(+80/-20 %)		E- 3 series
	Z5U			
	Y5U			

3.2 E series(standard Number)

Standard No.	Application Capacitance											
E- 3	1.0					2.2			4.7			
E- 6	1.0 1.5		2	2.2 3.3		4.7		6.8				
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
Ι	NPO	-55℃ ~ +125℃	25 ℃
	SL	-25℃ ~ +125℃	25 ℃
Π	X7R	-55℃ ~ +125℃	25°C
	X5R	-55° C ~ +85° C	25 ℃
	X6S	-55℃ ~ +105℃	25 ℃
	Y5V	-30°C ∼ +85°C	25 ℃
	Z5U	+10°C ~ +85°C	25 ℃
	Y5U	-30 °C ∼ +85 °C	25 ℃
	Other	-25 ℃ ~ +85℃	25 ℃

5. Storage Condition

Storage Temperature : 5 to 40 $^\circ\mathrm{C}$

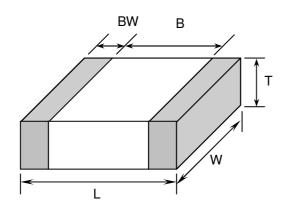
Relative Humidity : 20 to 70 %

Storage Time : 6 months max.



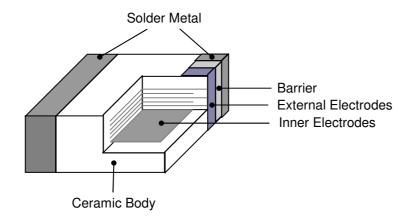
6. Dimensions

6.1 Configuration and Dimension :



					Unit:mm
TYPE	L	W	Т	B (min)	BW (min)
1206	3.20± 0.30	1.60± 0.20	1.60± 0.20	1.50	0.30

6.2 Termination Type :





7. Performance

No.	Item		5	Specific	ation	Test Condition		
1	Visua	al	No abnorma	exterio	r appearance	Visual inspection		
2	Dimens	ion	See Page 3			Visual inspection		
3	Insulati Resista		10,000MΩor Product Whit			V≦500V, Rated Voltage V>500V, Applied 500Vdc Charge Time∶60sec. Is applied less than 50mA current.		
	Capacitance	Class	Within The Sp	ecified	Tolerance			
4		I NPO/SL				Class I : NPO/SL		
		Class ∏	Within The Sp	ecified	Tolerance	$\begin{tabular}{ c c c c c c c } \hline Capacitance & Frequency & Voltage \\ \hline C \leq 100 pF & 1 MHz \pm 10\% & 1.0 \pm 0.2 Vrms \\ \hline C > 100 pF & 1 KHz \pm 10\% & \\ \hline \end{tabular}$		
5	Q	Class	More Than 30	pF:Q	≥1000	Class II :		
	Tan δ	I NPO/SL Class ∏	30pF & Below (C : Capacita Char. X7R Z5U/Y5U	.:Q≧40	00+20C	FrequencyVoltageX7R1KHz±10%1.0±0.2VrmsZ5U/Y5U1KHz±10%1.0±0.2VrmsPerform a heat temperature at 150±5℃ for 30min, then place room temp, for 24±2hr.		
6	Withstan	dina	No dielectric	breakd		V<500V : 200% Rated Voltage		
	Voltag	je	mechanical k	oreakdo	wn	 500V ≤ V < 1000V: 150% Rated Voltage 1000 ≤ V :120% Rated Voltage for 1~5 sec. Current is limited to less than 50mA. ※ Withstanding voltage testing requires immersion of the element in a isolation fluid prevent arcing on the chip surface, at voltage over 1000Vdc. 		
7	Temperature Capacitance Coefficient	Class I	Char. Temp. F NPO -55°℃~- SL -30°℃~-	+ 125 ℃	Cap. Change(%) ± 30 ppm/℃ +350~-1000ppm	[C2-C1/C1(T2-T1)] × 100% Class II :		
		Class ∏	Char. Temp. F X7R -55℃~~ Y5U -30℃~ Z5U +10℃~	+125℃ ′+85℃	Cap. Change(%) ± 15% +22% ~-56% +22% ~-56%	$(C2-C1)/C1 \times 100\%$ T1: Standard temperature ($25^{\circ}C$) T2: Test temperature C1:Capacitance at standard temperature($25^{\circ}C$) C2: Capacitance at test temperature (T2)		
8	Adhesive Strength of Termination Adhesive Strength the terminal electrode.			A 5N·f ($= 0.5$ Kg·f) pull force shall be applied for 10± 1 second. 5N·f				
9		Appear- ance			.	Bending shall be applied to the 1.0 mm with 1.0 mm/sec.		
	of Substrate	C-meter	Capacitance (Char. NPO SL X7R Y5U/Z5U	Cap ≦ ± ≦ ±	b. Change 5.0% 5.0% 12.5% 30.0%	C Meter 45±1mm 45±1mm		



No.	lte	m		Specif	ication			Test Condition	
10	Solder	ability	is to be		he terminal surface ewly, so metal part or dissolve .	[Solder Temperature : $245\pm5^{\circ}$ C Dip Time : 5 ± 0.5 sec. Immersing Speed : $25\pm10\%$ mm/s Solder : H63A Flux :Rosin		
11	Resistance To Soldering Heat	ance Capacit- ance Q Class I Tan ∂ Class II Insulation Resistance	Class (NPO/S Class II To sati To sati	aracteristic I SL) <u>X7R</u> <u>Z5U/Y5U</u> sfy the specif sfy the specif	Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value Within ± 10% Within ± 20% fied initial value fied initial value fied initial value fied initial value	C tro m I I	Preheat : At 80~120 °C for 10~30sec. Class II capacitor shall be set for 48±4 hours room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Preheat : At 150± 10 °C For 60~120sec. Dip : Solder Temperature of 260± 5 °C Dip Time : 10 ± 1sec. Immersing Speed : 25±10% mm/s Solder H63A Flux :Rosin Measure at room temperature after cooling for Class I : 24 ± 2 Hours Class II : 48 ± 4 Hours		
12	ture Cycle	Voltage Appear- ance Capacit- ance Q Class Ι Tan δ Class ΙΙ	No me Class (NPO/S Class II To sati To sati	chanical dam aracteristic I SL) X7R Z5U/Y5U sfy the specif	Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value Within ± 7.5% Within ± 20% fied initial value fied initial value	rc at (t	Class II capacitor shall be set for 48 ± 4 hours a room temperature after one hour heat treatmer at 150 +0/-10 °C before initial measure. Capacitor shall be subjected to five cycles of the temperature cycle as following: Step Temp.(°C) Time(min) 1 Min Rated Temp. +0/-3 30 2 25 3 3 Max Rated Temp. +3/-0 30 4 25 3 Measure at room temperature after cooling for Class I :24 ± 2 Hrs Class II :48 ± 4 Hrs		
13		Appear- ance Capacit- ance Q Class Ι Tan δ Class Ι Insulation Resistance	Class (NPO/S Class II More T 30pF & Cr X Z5U 1,000M	racteristic I SL) X7R Z5U/Y5U Than 30pF : C & Below: Q ≥ nar. 7R /Y5U MΩ or 50/C	hage shall occur Cap. Change Within \pm 5.0% or \pm 0.5pF whichever is larger of initial value Within \pm 15% Within \pm 30% $\Omega \ge 350$ $275 + 2.5 \times C$ Maximum 5.0% 5.0% Ω whichever is	C at tro M	Fig 2. lass II croom eatme leasur Fempe Relativ Fest Ti Clas Clas Solder	the capacitor on P.C. board shown in before testing. capacitor shall be set for 48 ± 4 hours temperature after one hour heat ent at $150\pm0/-10$ °C before initial re. erature : 40 ± 2 °C ve Humidity : $90 \sim 95\%$ RH ime : $500 \pm 12/-0$ Hr e at room temperature after cooling for as I : 24 ± 2 Hrs as II : 48 ± 4 Hrs r the capacitor on P.C. board shown in before testing.	

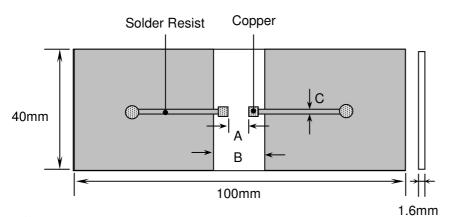


No.	Ite	m		Sp	ecifi	cation		Test C	ondition	
14	-	Appear- ance	No me	echanical	dam	age shall occur		ass II capacitors app bllowing table) is ap		
	Load	Capacit-	Ch	aracteristi		Cap. Change				
	Load	ance	Class			Within ±3.0% or		maximum operation temperature $\pm 3^{\circ}$ then		
		ance	(NPO/			± 0.3pFwhichever		shall be set for 48±4 hours at room temperatur		
				OL)		is larger		and the initial measurement shall be conducted.		
			Class	X7R		Within ± 15%				
			П	Z5U/Y5	5U	Within ± 30%	ΑĻ	oplied Voltage :		
		Q		Than 30pl				Rated Voltage	Applied Voltage	
		Class I			$c \geq c$	275 + 2.5× C		V≤250Vdc	150%Rated Voltage	
		Tan δ		nar.		maximum	_	Less Than 1KVdc	120%Rated Voltage	
		Class ∏		7R		5.0%	-	More Than	100%Rated Voltage	
		Inculation		/Y5U	<u> </u>	5.0%	_	1KVdc(include 1KV)	100%haleu vollage	
		Resistance				whichever is (C in Farad)	1210/100V capacitance more than 1.0uF			
		nesisiance	smalle	·.		(C III Farau)				
							ар	plied voltage of 120%	6 rated voltage	
								mperature : max. ope		
								st Time : 1000 +12/-0		
								urrent Applied : 50 m/		
								ass I : 24 \pm 2 Hours	erature after cooling for	
								ass II : 48 \pm 4 Hours		
15	Vibration	Appear-	No mo	chanical	dam	age shall occur			n P.C. Board shown in	
15	VIDIATION	ance		chanica	uam	age shall occur		ig 2. before testing.	ITT.O. DOAID SHOWITH	
		Capacit-	Cha	aracteristi	c	Cap. Change	1	.g		
		ance	Class		-	Within ± 2.5% or	V	ibrate the capacitor v	vith amplitude of 1.5mm	
			(NPO/	SL)		± 0.25pFwhichever	F	P-P changing the freq	uencies from 10Hz to	
			[.			is larger	5	5Hz and back to 10H	Iz in about 1 min.	
			Class	X7R		Within ± 7.5%				
			Π	Z5U/Y5		Within ± 20%			each in 3perpendicular	
		Q Class I	To sati	isfy the sp	becifi	ed initial value	air	rections.		
		Tan δ Class ∏	To sati	isfy the sp	pecifi	ed initial value				
			To sati	sfy the sr	ecifi	ed initial value	1			
		Resistance			20011					



Fig.1

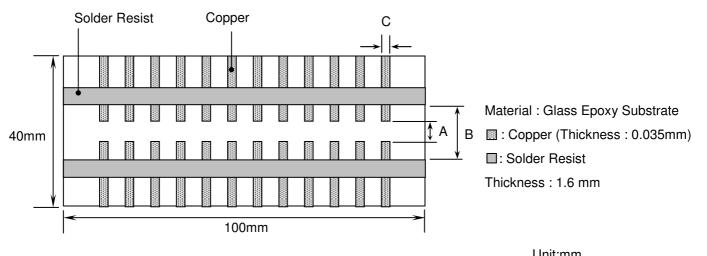
P.C. Board for Bending Strength Test



Material : Glass Epoxy Substrate : Copper (Thickness : 0.035mm) : Solder Resist

Fig.2

Test Substrate



			Unit:mm
Туре	A	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6

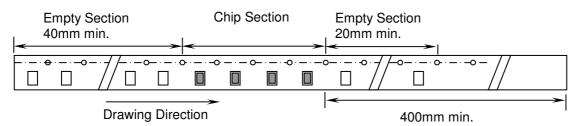


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/	/0805
Material	T≦0.33mm	T≦0.55mm	T≦0.90mm	T>0.90mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	1210/1808		
Material	T≦0.90mm	$0.90mm < T \le 1.25mm$	T>1.25mm	T≦1.25mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel	3000 pcs/Reel	2000 pcs/Reel

Tape	1812/1825	/2211/2220	22	2225		
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm	
Paper	NA	NA	NA	NA	NA	
Plastic	1000 pcs/Reel	700 pcs/Reel	1000 pcs/Reel	400 pcs/Reel	1000 pcs/Reel	

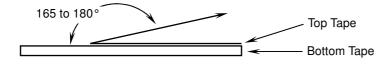
NA: Not Available

8.4 Cover Tape Reel Off Force

9.4.1 Peel-Off Force

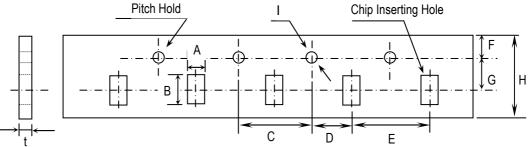
 $5 \text{ g·f} \leq \text{Peel-Off Force} \leq 70 \text{ g·f}$

9.4.2 Measure Method





8.5 Paper Tape

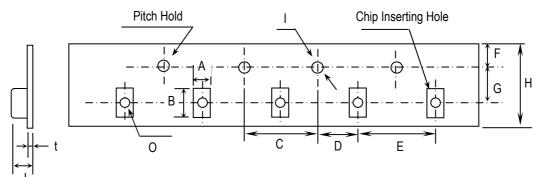


Unit:mm

TYPE	А	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60 ± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	<i>φ</i> 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Unit:mm

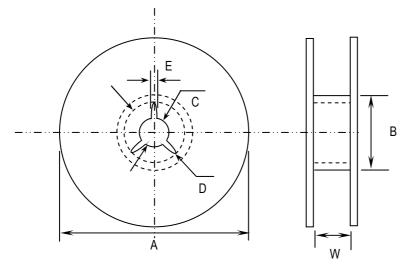
Туре	А	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0 ± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				



Туре	G	Н		J	t	0
0805	3.5± 0.05	8.0± 0.3	<i>φ</i> 1.5+0.1/-0	3.0 max.	0.3 max.	0.15 min.
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Туре	А	В	С	D	E	W
0201	φ 382 max	arphi 50 min	φ 13± 0.5	ϕ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	ϕ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						



Precautionary Notes:

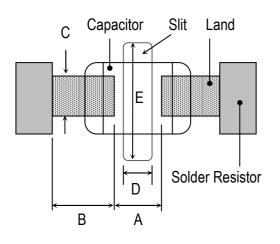
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 6 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

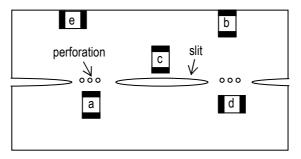
2.1 Size and recommend land dimensions for reflow soldering .



Chip (mm)		Land (mm)					
EIA Code	L	W	А	В	C	D	E
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board. Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



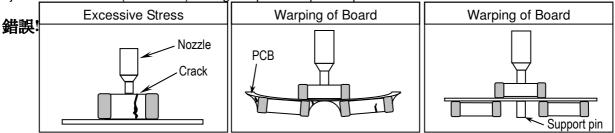


2.3 Layout Recommendation

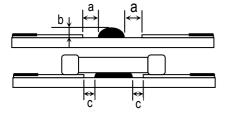
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Lead Wire Chip Solder	Chassis Excessive Solder Chassis	Solder Land
Recommendation	Lead Wire Chip Solder Resist	Solder Resist	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



Example : (0805 & 1206
-------------	-------------

a	0.2mm min.
b	70 ~ 100 µm
С	Do not touch the solder land

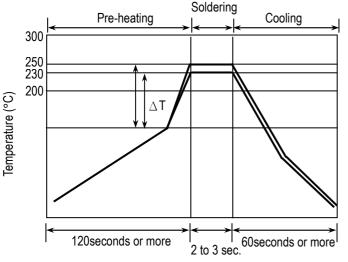


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to 250 °C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Change in Temp.(°C)
1206 and Under	∆ T ≤ 100~130 max.

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

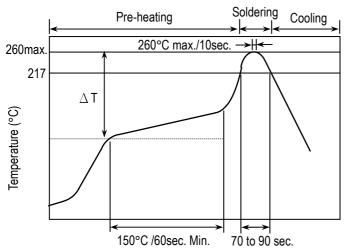
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed $3^{\circ}C/Sec$.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



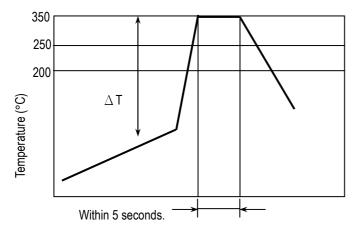
% The cycles of soldering : Twice (max.)

Soldering Method	Change in Temp.(°C)
1206 and Under	$\Delta T \leq 190 \ ^{\circ}C$
1210 and Over	∆T ≦ 130 °C



4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.($^{\circ}\mathbb{C}$)
1206 and Under	∆T ≦ 190 °C
1210 and Over	∆T ≦ 130 °C

How to Solder Repair by Solder Iron

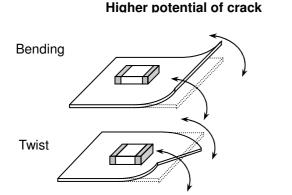
1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

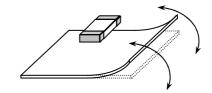
- 2) recommended solder iron condition
 - a.) Preheat the substrate to (60 °C to 120 °C) on a hot plate. Note that due to the heat loss, the actual setting of the hot plate may have to be higher. (For example 100 °C to 150 °C)
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350 °C., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.



Lower potential of crack



5.2 There is a potential of crack if board is warped due to excessive load by check pin



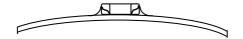


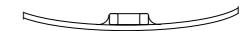
5.3 Mechanical stress due to warping and torsion.

- (a) Crack occurrence ratio will be increased by manual separation.
- (b) Crack occurrence ratio will be increased by tensile force , rather than compressive force.

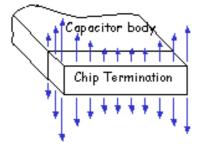
imes :Tensile Stress

O :Compressive Stress





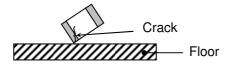
Capacitor Stress Analysis



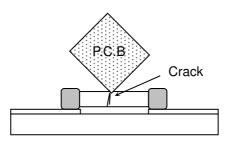


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 $^{\circ}$ C and under humidity of 20 to 75% RH. The shelf life of capacitors is 6 months.